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Dated: June 30, 2003

Signature: 
(Gregory S. Gewirtz)



6p2812
Docket No.: 01 P 06119US
INTECH 3.0-047
(PATENT)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:
Schafbauer et al.

Application No.: 09/826,732

Group Art Unit: 2812

Filed: April 5, 2001

Examiner: Not Yet Assigned

For: STRUCTURE AND METHOD FOR
DETERMINING EDGES OF REGIONS IN A
SEMICONDUCTOR WAFER

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

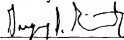
Dear Sir:

It is respectfully requested that the references listed on the enclosed form be made of record and considered with respect to the above-referenced U.S. patent application. A copy of each reference is enclosed. Submission of the present Information Disclosure Statement should not be taken as an admission that the cited references are legally available prior art or that the same are pertinent or material.

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Dated: June 30, 2003

Respectfully submitted,

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Substitute for form 1449-PTO		Complete If Known	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)		Application Number	09/826,732
		Filing Date	April 5, 2001
		First Named Inventor	Thomas Schafbauer
		Art Unit	2812
		Examiner Name	Not Yet Assigned
		Attorney Docket Number	99 INTECH 3.0-047
Sheet	1	of	1

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
	AA	US-6,118,137		Fulford, Jr. et al.	
	AB	US-5,861,679		Nagano	
	AC	US-5,699,282		Allen et al.	
	AD	US-5,256,577		Plunkke et al.	

FOREIGN PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Foreign Patent Document Country Code ³ -Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear

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NON PATENT LITERATURE DOCUMENTS					
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.			
	CA	Patent Abstracts of Japan, Vol. 006, no. 119 (E-116), 3 July 1982 (1982-07-03 & JP 57 045946 A (NEC Corp), 16 March 1982 (1982-03-15) abstract, figure 1			
	CB	Patent Abstracts of Japan, vol. 016, no. 200 (E-1201), 13 May 1992 (1992-05-13) & JP 04 032216 A (Mitsubishi Electric Corp.), 4 February 1992 (1992-02-04) abstract, figures 1-8			
	CC	Patent Abstracts of Japan, vol 1995, no. 10, 30 November 1995 (1995-11-30 & JP 07 183351 A (Matsushita Electron Corp), 21 July 1995 (1995-07-21) abstract, figures 1-3)			
	CD	Patent Abstracts of Japan, Vol 015, no. 036 (E-1027), 29 January 1991 (1991-01-29) & JP 02 273954 A (Fujitsu Ltd), 8 November 1990 (1990-11-08) abstract, figures 1-8			
	CE	Patent Abstracts of Japan, vol. 008, no. 142 (E-254), 3 July 1984 (1984-07-03) & JP 59 051529 A (Matsushita Denki Sangyo KK), 26 March 1984 (1984-03-26) abstract; figures 2, 3, 5-7			
	CF	International Search Report			

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